

# P-Channel 60-V (D-S) MOSFET

PRODUCT SUMMARY		
V <sub>DS</sub>	-60	V
$R_{DS(on)}$ $V_{GS} = 10$ V	19	mΩ
$R_{DS(on)}$ $V_{GS} = 4.5 V$	26	mΩ
I <sub>D</sub>	-50	А
Configuration	Sin	gle

# TO-220AB

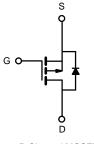
## FEATURES

- TrenchFET<sup>®</sup> Power MOSFET
  100 % UIS Tested

### APPLICATIONS

Load Switch





P-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b>	<b>S</b> (T <sub>A</sub> = 25 °C, unle	ess otherwise no	oted)		
Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V <sub>DS</sub>	- 60	V	
Gate-Source Voltage		V <sub>GS</sub>	± 20	v	
	T <sub>C</sub> = 25 °C		- 50		
Continuous Drain Current (T 150 °C)	T <sub>C</sub> = 70 °C		- 46		
Continuous Drain Current ( $T_J = 150 \ ^{\circ}C$ )	T <sub>A</sub> = 25 °C	I <sub>D</sub>	-39	_	
	T <sub>A</sub> = 70 °C		-34	A	
Pulsed Drain Current		I <sub>DM</sub>	- 200		
Avalanche Current Pulse	$\begin{array}{c c} & & & & & & \\ & & & & & & \\ \hline T_{C} = 25 \ ^{\circ}C \\ \hline T_{C} = 70 \ ^{\circ}C \\ \hline T_{A} = 25 \ ^{\circ}C \\ \hline T_{A} = 70 \ ^{\circ}C \\ \hline \end{array}$	I <sub>AS</sub>	- 45		
Single Pulse Avalanche Energy	L = 0.1 IIIH	E <sub>AS</sub>	101	mJ	
	T <sub>C</sub> = 25 °C	L.	69 <sup>a</sup>	A	
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	20 <sup>b</sup>		
	T <sub>C</sub> = 25 °C		104.2 <sup>a</sup>		
Maximum Davies Dissingtion	T <sub>C</sub> = 70 °C		66.7 <sup>a</sup>	w	
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	3.1 <sup>b</sup>	vv	
	T <sub>A</sub> = 70 °C		2 <sup>b</sup>		
Operating Junction and Storage Temperature Ra	ange	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS					
Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient <sup>b</sup>	Steady State	R <sub>thJA</sub>	33	40	°C/W
Maximum Junction-to-Case	Steady State	R <sub>thJC</sub>	0.98	1.2	0/00

Notes:

a. Based on  $T_C = 25 \ ^{\circ}C$ .

b. Surface mounted on 1" x 1" FR4 board.

<b>SPECIFICATIONS</b> ( $T_J = 25 \ ^{\circ}C$ ,	unless othe	erwise noted)				
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static		·		•	•	•
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 V, I_D = -250 \mu A$	- 60			V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = - 250 μA		68		mV/°C
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	η 200 μΛ		- 5.2		mv/ C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = -250 \ \mu A$	- 1		- 3	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA
Zure Oaks Malla an Daris Ourseal		$V_{DS} = -60 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			- 1	
Zero Gate Voltage Drain Current	IDSS	$V_{DS}$ = - 60 V, $V_{GS}$ = 0 V, $T_{J}$ = 55 °C			- 10	μA
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	V <sub>DS</sub> = - 5 V, V <sub>GS</sub> = - 10 V	- 120			А
		V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 30 A		19		
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = - 4.5 V, I <sub>D</sub> = - 20 A		26		mΩ
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = - 15 V, I <sub>D</sub> = - 50 A	20			S
Dynamic <sup>b</sup>				•	•	
Input Capacitance	C <sub>iss</sub>			3700		
Output Capacitance	C <sub>oss</sub>	$V_{DS}$ = - 25 V, $V_{GS}$ = 0 V, f = 1 MHz		390		pF
Reverse Transfer Capacitance	C <sub>rss</sub>			290		
Tatal Cata Charge		$V_{DS} = -30$ V, $V_{GS} = -10$ V, $I_{D} = -55$ A		76	115	
Total Gate Charge	Qg			38	60	~ ~ ~
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS} = -30$ V, $V_{GS} = -4.5$ V, $I_{D} = -55$ A		16		nC
Gate-Drain Charge	Q <sub>gd</sub>			19		
Gate Resistance	Rg	f = 1 MHz		5.2		Ω
Turn-On Delay Time	t <sub>d(on)</sub>			10	15	
Rise Time	t <sub>r</sub>	$V_{DD}$ = - 2 V, $R_L$ = 2 $\Omega$		7	15	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_{D}\cong$ - 10 A, $V_{GEN}$ = - 10 V, $R_{g}$ = 1 $\Omega$		70	110	ns
Fall Time	t <sub>f</sub>			40	60	
Drain-Source Body Diode Characteristic	S			1	1	1
Continuous Source-Drain Diode Current	۱ <sub>S</sub>	T <sub>C</sub> = 25 °C			- 69	^
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				- 150	A
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = - 30 A		- 1	- 1.5	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>			45	68	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			59	120	nC
Reverse Recovery Fall Time	t <sub>a</sub>	I <sub>F</sub> = - 50 A, di/dt = 100 A/μs, T <sub>J</sub> = 25 °C		29		
Reverse Recovery Rise Time	t <sub>b</sub>	1		16		ns

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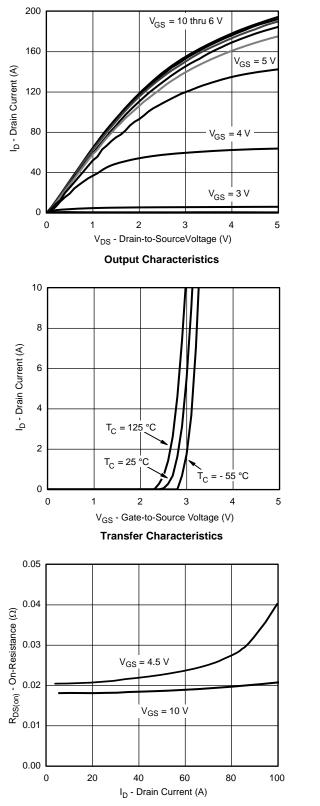
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Notes:

a. Pulse test; pulse width  $\leq$  300  $\mu s,$  duty cycle  $\leq$  2 %. b. Guaranteed by design, not subject to production testing.

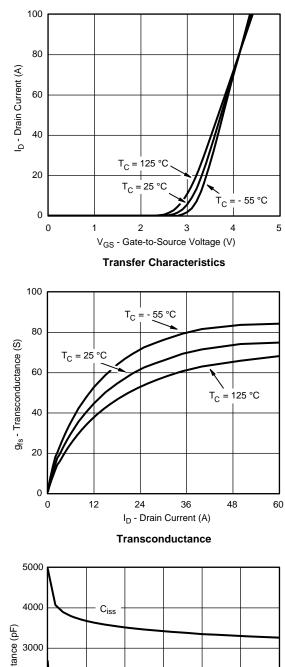
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

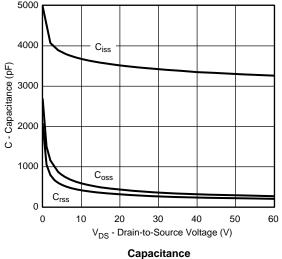




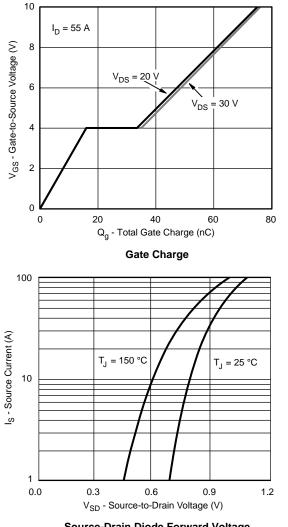
### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

**On-Resistance vs. Drain Current** 



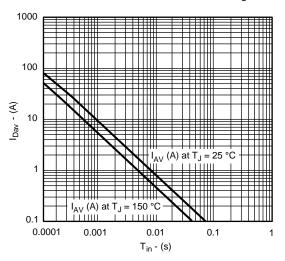




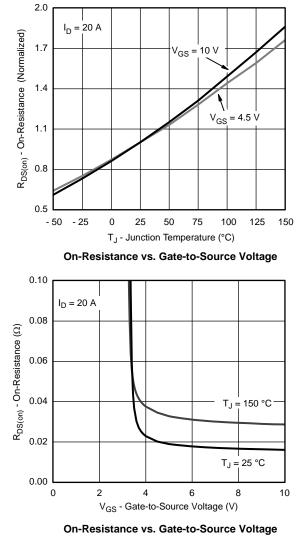


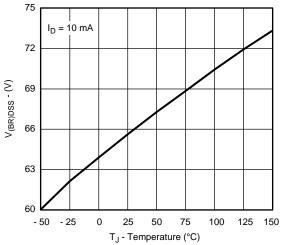
### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

Source-Drain Diode Forward Voltage



Single Pulse Avalanche Current Capability vs. Time

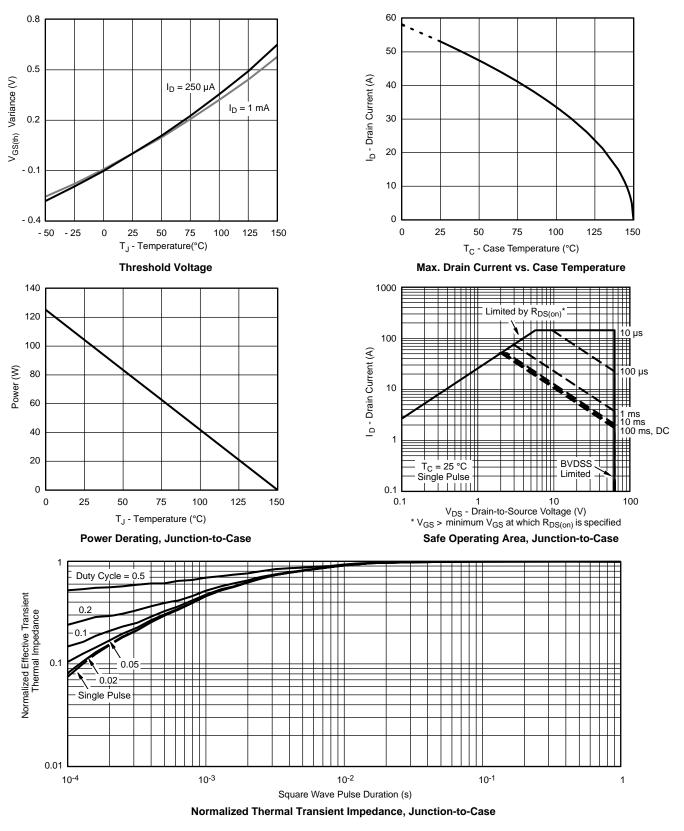




Drain-Source Breakdown Voltage vs. Junction Temperature

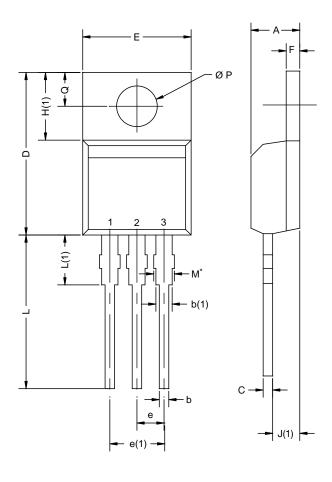


### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)





# **TO-220AB**



	MILLIN	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØР	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	

### Notes

\* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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